Se	arcn Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/612,040	CHOI ET AL.
Examiner	Art Unit
Tianjie Chen	2627

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Class	Subclass	Date	Examiner
Updated		1/8/2007	TJ
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TMI	INTERFERENCE SEARCHED		
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DATE  1/8/2007	TJ
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